

**Search Notes**

Application/Control No.

10/500,540

Examiner

Sargon N. Nano

Applicant(s)/Patent under  
Reexamination

RYUKAWA ET AL.

Art Unit

2157

**SEARCHED**

Class	Subclass	Date	Examiner
709	208, 212 227	2/2/2007	SN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (see attached report)	2/2/2007	SN